Special Issue

Deep Learning for Object Detection

Message from the Guest Editor

Currently, models based on convolutional neural networks (CNNs) are increasingly being applied for image classification due to their ability to handle big data. Models such as you only look once (YOLO) have become very popular for having greater flexibility and good performance in object identification. In this Special Issue, we are aiming to collate studies on all of the aspects surrounding “Deep Learning for Object Detection”. Any original, unpublished work is welcome. If you have an interest in this topic, please let us know.

Guest Editor

Dr. Stéfano Frizzo Stefenon
Digital Industry Center, Fondazione Bruno Kessler, 18, 38123 Trento, Italy

Deadline for manuscript submissions

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Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,
20133 Milano, Italy

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